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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e300c2
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	266MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100Mbps (3)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	516-BBGA
Supplier Device Package	516-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8323zqaddc

1.1.2 Serial Interfaces

The MPC8323E serial interfaces are as follows:

- Support for one UL2 interface with 31 multi-PHY addresses (MPC8323E and MPC8323 only)
- Support for up to three 10/100 Mbps Ethernet interfaces using MII or RMII
- Support for up to four T1/E1/J1/E3 or DS-3 serial interfaces (TDM)
- Support for dual UART and SPI interfaces and a single I^2C interface

1.2 QUICC Engine Block

The QUICC Engine block is a versatile communications complex that integrates several communications peripheral controllers. It provides on-chip system design for a variety of applications, particularly in communications and networking systems. The QUICC Engine block has the following features:

- One 32-bit RISC controller for flexible support of the communications peripherals
- Serial DMA channel for receive and transmit on all serial channels
- Five universal communication controllers (UCCs) supporting the following protocols and interfaces (not all of them simultaneously):
  - 10/100 Mbps Ethernet/IEEE 802.3® standard
  - IP support for IPv4 and IPv6 packets including TOS, TTL, and header checksum processing
  - ATM protocol through UTOPIA interface (note that the MPC8321 and MPC8321E do not support the UTOPIA interface)
  - HDLC /transparent up to 70-Mbps full-duplex
  - HDLC bus up to 10 Mbps
  - Asynchronous HDLC
  - UART
  - BISYNC up to 2 Mbps
  - QUICC multi-channel controller (QMC) for 64 TDM channels
- One UTOPIA interface (UPC1) supporting 31 multi-PHYs (MPC8323E- and MPC8323-specific)
- Two serial peripheral interfaces (SPI). SPI2 is dedicated to Ethernet PHY management.
- Four TDM interfaces
- Thirteen independent baud rate generators and 19 input clock pins for supplying clocks to UCC serial channels
- Four independent 16-bit timers that can be interconnected as two 32-bit timers

The UCCs are similar to the PowerQUICC II peripherals: SCC (BISYNC, UART, and HDLC bus) and FCC (fast Ethernet, HDLC, transparent, and ATM).

Table 6. Estimated Typical I/O Power Dissipation (continued)

Local bus I/O load = 25 pF 1 pair of clocks	66 MHz, 32 bits	—	—	0.12	W	—
PCI I/O load = 30 pF	66 MHz, 32 bits	—	—	0.057	W	—
QUICC Engine block and other I/Os	UTOPIA 8-bit 31 PHYs	—	—	0.041	W	Multiply by number of interfaces used.
	TDM serial	—	—	0.001	W	
	TDM nibble	—	—	0.004	W	
	HDLC/TRAN serial	—	—	0.003	W	
	HDLC/TRAN nibble	—	—	0.025	W	
	DUART	—	—	0.017	W	
	MIIs	—	—	0.009	W	
	RMII	—	—	0.009	W	
	Ethernet management	—	—	0.002	W	
	USB	—	—	0.001	W	
	SPI	—	—	0.001	W	
	Timer output	—	—	0.002	W	

NOTE

$AV_{DD}n$ (1.0 V) is estimated to consume 0.05 W (under normal operating conditions and ambient temperature).

4 Clock Input Timing

This section provides the clock input DC and AC electrical characteristics for the MPC8323E.

NOTE

The rise/fall time on QUICC Engine input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of VCC; fall time refers to transitions from 90% to 10% of VCC.

4.1 DC Electrical Characteristics

Table 7 provides the clock input (CLKIN/PCI_SYNC_IN) DC timing specifications for the MPC8323E.

Table 7. CLKIN DC Electrical Characteristics

Parameter	Condition	Symbol	Min	Max	Unit
Input high voltage	—	V_{IH}	2.7	OV_{DD} + 0.3	V
Input low voltage	—	V_{IL}	–0.3	0.4	V

Table 7. CLKIN DC Electrical Characteristics (continued)

CLKIN input current	$0 V \le V_{IN} \le OV_{DD}$	I_{IN}	—	±5	μA
PCI_SYNC_IN input current	$0 V \le V_{IN} \le 0.5 V$ or $OV_{DD} - 0.5 V \le V_{IN} \le OV_{DD}$	I_{IN}	—	±5	μA
PCI_SYNC_IN input current	$0.5 V \le V_{IN} \le OV_{DD} - 0.5 V$	I_{IN}	—	±50	μA

4.2 AC Electrical Characteristics

The primary clock source for the MPC8323E can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Table 8 provides the clock input (CLKIN/PCI_CLK) AC timing specifications for the MPC8323E.

Table 8. CLKIN AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
CLKIN/PCI_CLK frequency	f_{CLKIN}	25	—	66.67	MHz	1
CLKIN/PCI_CLK cycle time	t_{CLKIN}	15	—	—	ns	—
CLKIN rise and fall time	t_{KH}, t_{KL}	0.6	0.8	4	ns	2
PCI_CLK rise and fall time	t_{PCH}, t_{PCL}	0.6	0.8	1.2	ns	2
CLKIN/PCI_CLK duty cycle	t_{KHK}/t_{CLKIN}	40	—	60	%	3
CLKIN/PCI_CLK jitter	—	—	—	±150	ps	4, 5

Notes:
1. **Caution:** The system, core, security, and QUICC Engine block must not exceed their respective maximum or minimum operating frequencies.
2. Rise and fall times for CLKIN/PCI_CLK are measured at 0.4 and 2.7 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The CLKIN/PCI_CLK driver's closed loop jitter bandwidth should be < 500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track CLKIN drivers with the specified jitter.

5 RESET Initialization

This section describes the AC electrical specifications for the reset initialization timing requirements of the MPC8323E. Table 9 provides the reset initialization AC timing specifications for the reset component(s).

Table 9. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$ or $\overline{\text{SRESET}}$ (input) to activate reset flow	32	—	$t_{PCI\_SYNC\_IN}$	1
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to CLKIN when the MPC8323E is in PCI host mode	32	—	t_{CLKIN}	2
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to PCI_SYNC_IN when the MPC8323E is in PCI agent mode	32	—	$t_{PCI\_SYNC\_IN}$	1

6.2 DDR1 and DDR2 SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR1 and DDR2 SDRAM interface.

6.2.1 DDR1 and DDR2 SDRAM Input AC Timing Specifications

Table 16 provides the input AC timing specifications for the DDR2 SDRAM (D*n*_GV_{DD}(typ) = 1.8 V).

Table 16. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with D*n*_GV_{DD} of 1.8 ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MVREFn_{REF} – 0.25	V	—
AC input high voltage	V_{IH}	MVREFn_{REF} + 0.25	—	V	—

Table 17 provides the input AC timing specifications for the DDR1 SDRAM (D*n*_GV_{DD}(typ) = 2.5 V).

Table 17. DDR1 SDRAM Input AC Timing Specifications for 2.5 V Interface

At recommended operating conditions with D*n*_GV_{DD} of 2.5 ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MVREFn_{REF} – 0.31	V	—
AC input high voltage	V_{IH}	MVREFn_{REF} + 0.31	—	V	—

Table 18 provides the input AC timing specifications for the DDR1 and DDR2 SDRAM interface.

Table 18. DDR1 and DDR2 SDRAM Input AC Timing Specifications

At recommended operating conditions with D*n*_GV_{DD} of (1.8 or 2.5 V) ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
Controller skew for MDQS—MDQ/MDM	t_{CISKEW}			ps	1, 2
266 MHz		–750	750		
200 MHz		–1250	1250		

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that is captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW}. This can be determined by the following equation: $t_{DISKEW} = \pm(T/4 - abs(t_{CISKEW}))$ where T is the clock period and $abs(t_{CISKEW})$ is the absolute value of t_{CISKEW}.

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the MPC8323E.

7.1 DUART DC Electrical Characteristics

Table 20 provides the DC electrical characteristics for the DUART interface of the MPC8323E.

Table 20. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage OV_{DD}	V_{IL}	–0.3	0.8	V
High-level output voltage, I_{OH} = –100 µA	V_{OH}	OV_{DD} – 0.2	—	V
Low-level output voltage, I_{OL} = 100 µA	V_{OL}	—	0.2	V
Input current (0 V ≤ V_{IN} ≤ OV_{DD})[1]	I_{IN}	—	±5	µA

Note:
1. Note that the symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.2 DUART AC Electrical Specifications

Table 21 provides the AC timing parameters for the DUART interface of the MPC8323E.

Table 21. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	256	baud	
Maximum baud rate	> 1,000,000	baud	1
Oversample rate	16	—	2

Notes:
1. Actual attainable baud rate is limited by the latency of interrupt processing.
2. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Ethernet and MII Management

This section provides the AC and DC electrical characteristics for Ethernet and MII management.

8.1 Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics

The electrical characteristics specified here apply to all MII (media independent interface) and RMII (reduced media independent interface), except MDIO (management data input/output) and MDC

Table 23. MII Transmit AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
TX_CLK data clock fall time	t_{MTXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 7 shows the MII transmit AC timing diagram.

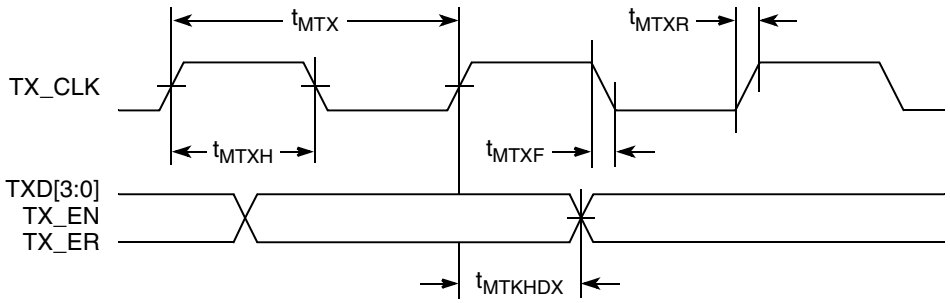


Figure 7. MII Transmit AC Timing Diagram

8.2.1.2 MII Receive AC Timing Specifications

Table 24 provides the MII receive AC timing specifications.

Table 24. MII Receive AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time	t_{MRXR}	1.0	—	4.0	ns

Table 30. Local Bus General Timing Parameters (continued)

Parameter	Symbol[1]	Min	Max	Unit	Notes
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7
Local bus clock (LCLK*n*) to output valid	t_{LBKHOV}	—	3	ns	3
Local bus clock (LCLK*n*) to output high impedance for LAD/LDP	t_{LBKHOZ}	—	4	ns	8
Local bus clock (LCLK*n*) duty cycle	t_{LBDC}	47	53	%	—
Local bus clock (LCLK*n*) jitter specification	t_{LBRJ}	—	400	ps	—
Delay between the input clock (PCI_SYNC_IN) of local bus output clock (LCLK*n*)	t_{LBCDL}	—	1.7	ns	—

Notes:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1).
2. All timings are in reference to falling edge of LCLK0 (for all outputs and for $\overline{\text{LGTA}}$ and LUPWAIT inputs) or rising edge of LCLK0 (for all other inputs).
3. All signals are measured from $OV_{DD}/2$ of the rising/falling edge of LCLK0 to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ should be used when RCWH[LALE] is not set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
6. $t_{LBOTOT2}$ should be used when RCWH[LALE] is set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
7. $t_{LBOTOT3}$ should be used when RCWH[LALE] is set and the load on LALE output pin equals to the load on LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

Figure 14 provides the AC test load for the local bus.

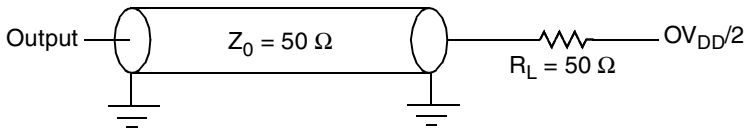


Figure 14. Local Bus C Test Load

Table 31. JTAG Interface DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

10.2 JTAG AC Electrical Characteristics

This section describes the AC electrical specifications for the IEEE Std. 1149.1 (JTAG) interface of the MPC8323E. Table 32 provides the JTAG AC timing specifications as defined in Figure 19 through Figure 22.

Table 32. JTAG AC Timing Specifications (Independent of CLKIN)[1]

At recommended operating conditions (see Table 2).

Parameter	Symbol[2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	11	—	ns	—
JTAG external clock rise and fall times	t_{JTGR}, t_{JTGF}	0	2	ns	—
$\overline{TRST}$ assert time	t_{TRST}	25	—	ns	3
Input setup times: Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 4	 — —	ns	4
Input hold times: Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 10 10	 — —	ns	4
Valid times: Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 2 2	 15 15	ns	5
Output hold times: Boundary-scan data TDO	 t_{JTKLDX} t_{JTKLOX}	 2 2	 — —	ns	5

Figure 21 provides the boundary-scan timing diagram.

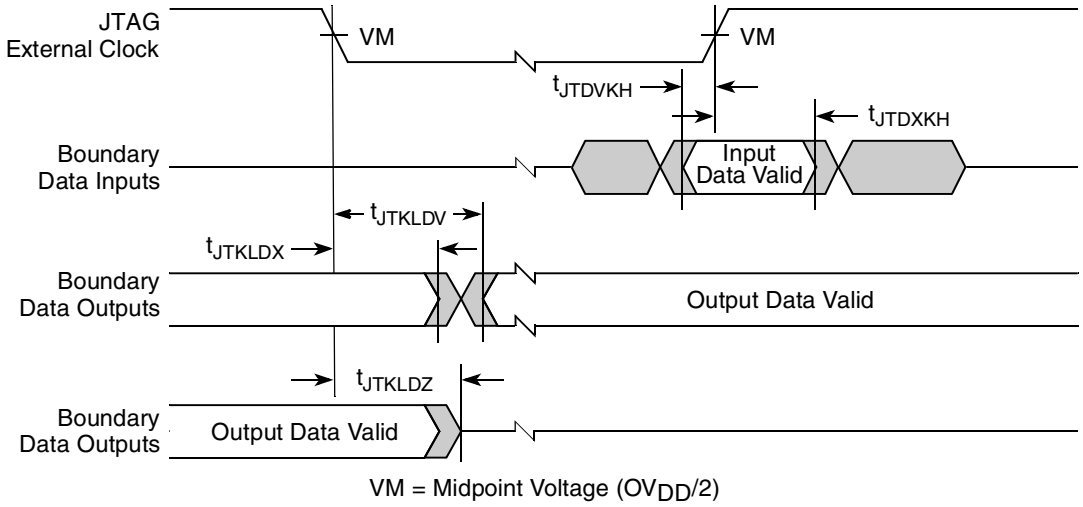


Figure 21. Boundary-Scan Timing Diagram

Figure 22 provides the test access port timing diagram.

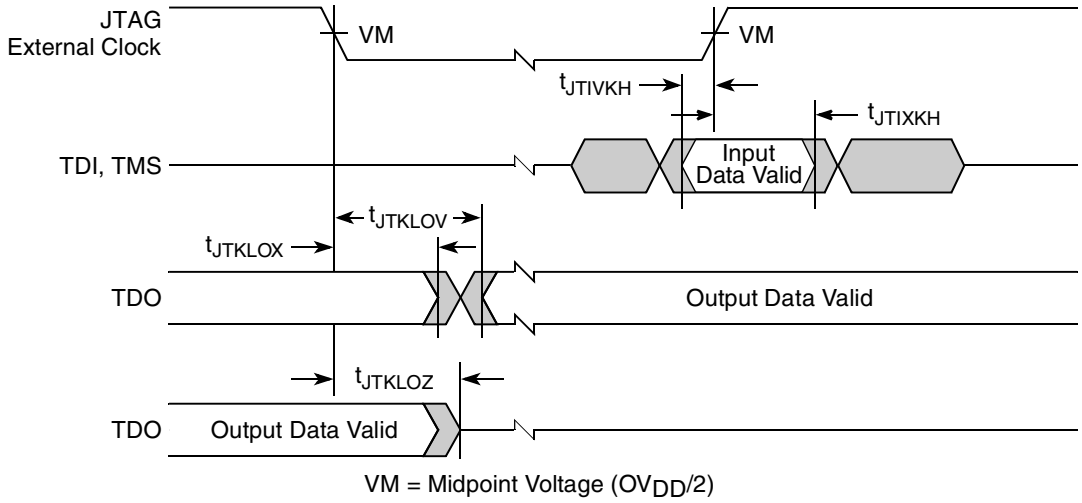


Figure 22. Test Access Port Timing Diagram

Figure 29 provides the AC test load for the GPIO.

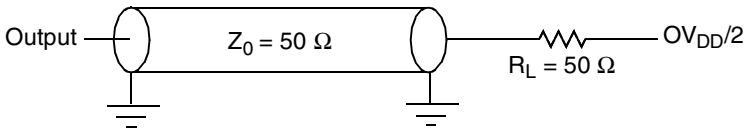


Figure 29. GPIO AC Test Load

15 IPIC

This section describes the DC and AC electrical specifications for the external interrupt pins of the MPC8323E.

15.1 IPIC DC Electrical Characteristics

Table 42 provides the DC electrical characteristics for the external interrupt pins of the MPC8323E.

Table 42. IPIC DC Electrical Characteristics[1,2]

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	—	—	±5	μA
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V

Notes:
1. This table applies for pins $\overline{\text{IRQ}}$[0:7], $\overline{\text{IRQ\_OUT}}$, $\overline{\text{MCP\_OUT}}$, and CE ports Interrupts.
2. $\overline{\text{IRQ\_OUT}}$ and $\overline{\text{MCP\_OUT}}$ are open drain pins, thus V_{OH} is not relevant for those pins.

15.2 IPIC AC Timing Specifications

Table 43 provides the IPIC input and output AC timing specifications.

Table 43. IPIC Input AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Unit
IPIC inputs—minimum pulse width	t_{PIWID}	20	ns

Notes:
1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.
2. IPIC inputs and outputs are asynchronous to any visible clock. IPIC outputs should be synchronized before use by any external synchronous logic. IPIC inputs are required to be valid for at least t_{PIWID} ns to ensure proper operation when working in edge triggered mode.

16 SPI

This section describes the DC and AC electrical specifications for the SPI of the MPC8323E.

16.1 SPI DC Electrical Characteristics

Table 44 provides the DC electrical characteristics for the MPC8323E SPI.

Table 44. SPI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	0 V ≤ V_{IN} ≤ OV_{DD}	—	±5	μA

16.2 SPI AC Timing Specifications

Table 45 and provide the SPI input and output AC timing specifications.

Table 45. SPI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
SPI outputs—Master mode (internal clock) delay	t_{NIKHOV}	0.5	6	ns
SPI outputs—Slave mode (external clock) delay	t_{NEKHOV}	2	8	ns
SPI inputs—Master mode (internal clock) input setup time	t_{NIIVKH}	6	—	ns
SPI inputs—Master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns
SPI inputs—Slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns
SPI inputs—Slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

Figure 30 provides the AC test load for the SPI.

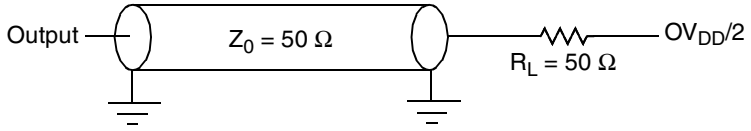


Figure 30. SPI AC Test Load

Table 46. TDM/SI DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

17.2 TDM/SI AC Timing Specifications

Table 47 provides the TDM/SI input and output AC timing specifications.

Table 47. TDM/SI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
TDM/SI outputs—External clock delay	t_{SEKHOV}	2	12	ns
TDM/SI outputs—External clock High Impedance	t_{SEKHOX}	2	10	ns
TDM/SI inputs—External clock input setup time	t_{SEIVKH}	5	—	ns
TDM/SI inputs—External clock input hold time	t_{SEIXKH}	2	—	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{SEKHOX} symbolizes the TDM/SI outputs external timing (SE) for the time $t_{TDM/SI}$ memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

Figure 33 provides the AC test load for the TDM/SI.

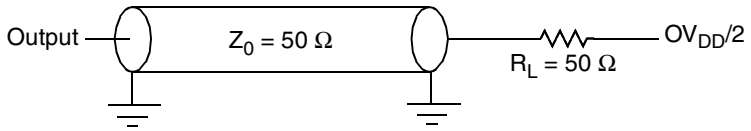
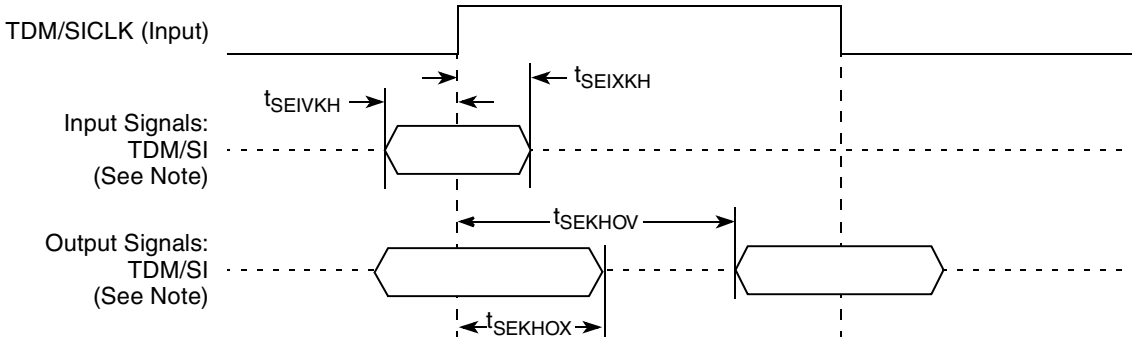


Figure 33. TDM/SI AC Test Load

Figure 34 represents the AC timing from Table 47. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.



Note: The clock edge is selectable on TDM/SI.

Figure 34. TDM/SI AC Timing (External Clock) Diagram

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{LCS1}}$	AB25	O	OV_{DD}	4
$\overline{\text{LCS2}}$	AA23	O	OV_{DD}	4
$\overline{\text{LCS3}}$	AA24	O	OV_{DD}	4
$\overline{\text{LWE0}}$	Y23	O	OV_{DD}	4
$\overline{\text{LWE1}}$	W25	O	OV_{DD}	4
LBCTL	V25	O	OV_{DD}	4
LALE	V24	O	OV_{DD}	7
CFG_RESET_SOURCE[0]/LSDA10/LGPL0	L23	IO	OV_{DD}	—
CFG_RESET_SOURCE[1]/$\overline{\text{LSDWE}}$/LGPL1	K23	IO	OV_{DD}	—
$\overline{\text{LSDRAS}}$/LGPL2/$\overline{\text{LOE}}$	J23	O	OV_{DD}	4
CFG_RESET_SOURCE[2]/$\overline{\text{LSDCAS}}$/LGPL3	H23	IO	OV_{DD}	—
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/LPBSE	G23	IO	OV_{DD}	4, 8
LGPL5	AC22	O	OV_{DD}	4
LCLK0	Y24	O	OV_{DD}	7
LCLK1	Y25	O	OV_{DD}	7
DUART				
UART_SOUT1/MSRCID0 (DDR ID)/LSRCID0	G1	IO	OV_{DD}	—
UART_SIN1/MSRCID1 (DDR ID)/LSRCID1	G2	IO	OV_{DD}	—
$\overline{\text{UART\_CTS1}}$/MSRCID2 (DDR ID)/LSRCID2	H3	IO	OV_{DD}	—
$\overline{\text{UART\_RTS1}}$/MSRCID3 (DDR ID)/LSRCID3	K3	IO	OV_{DD}	—
UART_SOUT2/MSRCID4 (DDR ID)/LSRCID4	H2	IO	OV_{DD}	—
UART_SIN2/MDVAL (DDR ID)/LDVAL	H1	IO	OV_{DD}	—
$\overline{\text{UART\_CTS2}}$	J3	IO	OV_{DD}	—
$\overline{\text{UART\_RTS2}}$	K4	IO	OV_{DD}	—
I^2C interface				
IIC_SDA/$\overline{\text{CKSTOP\_OUT}}$	AE24	IO	OV_{DD}	2
IIC_SCL/$\overline{\text{CKSTOP\_IN}}$	AF24	IO	OV_{DD}	2
Programmable Interrupt Controller				
$\overline{\text{MCP\_OUT}}$	AD25	O	OV_{DD}	—
$\overline{\text{IRQ0}}$/$\overline{\text{MCP\_IN}}$	AD26	I	OV_{DD}	—
$\overline{\text{IRQ1}}$	K1	IO	OV_{DD}	—
$\overline{\text{IRQ2}}$	K2	I	OV_{DD}	—

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
CE/GPIO				
GPIO_PA0/SER1_TXD[0]/TDMA_TXD[0]/USBTXN	G3	IO	OV_{DD}	—
GPIO_PA1/SER1_TXD[1]/TDMA_TXD[1]/USBTXP	F3	IO	OV_{DD}	—
GPIO_PA2/SER1_TXD[2]/TDMA_TXD[2]	F2	IO	OV_{DD}	—
GPIO_PA3/SER1_TXD[3]/TDMA_TXD[3]	E3	IO	OV_{DD}	—
GPIO_PA4/SER1_RXD[0]/TDMA_RXD[0]/USBRXP	E2	IO	OV_{DD}	—
GPIO_PA5/SER1_RXD[1]/TDMA_RXD[1]/USBRXN	E1	IO	OV_{DD}	—
GPIO_PA6/SER1_RXD[2]/TDMA_RXD[2]/USBRXD	D3	IO	OV_{DD}	—
GPIO_PA7/SER1_RXD[3]/TDMA_RXD[3]	D2	IO	OV_{DD}	—
GPIO_PA8/SER1_CD/TDMA_REQ/$\overline{\text{USBOE}}$	D1	IO	OV_{DD}	—
GPIO_PA9 TDMA_CLKO	C3	IO	OV_{DD}	—
GPIO_PA10/SER1_CTS/TDMA_RSYNC	C2	IO	OV_{DD}	—
GPIO_PA11/TDMA_STROBE	C1	IO	OV_{DD}	—
GPIO_PA12/SER1_RTS/TDMA_TSYNC	B1	IO	OV_{DD}	—
GPIO_PA13/CLK9/BRGO9	H4	IO	OV_{DD}	—
GPIO_PA14/CLK11/BRGO10	G4	IO	OV_{DD}	—
GPIO_PA15/BRGO7	J4	IO	OV_{DD}	—
GPIO_PA16/ LA0 (LBIU)	K24	IO	OV_{DD}	—
GPIO_PA17/ LA1 (LBIU)	K26	IO	OV_{DD}	—
GPIO_PA18/Enet2_TXD[0]/SER2_TXD[0]/ TDMB_TXD[0]/LA2 (LBIU)	G25	IO	OV_{DD}	—
GPIO_PA19/Enet2_TXD[1]/SER2_TXD[1]/ TDMB_TXD[1]/LA3 (LBIU)	G26	IO	OV_{DD}	—
GPIO_PA20/Enet2_TXD[2]/SER2_TXD[2]/ TDMB_TXD[2]/LA4 (LBIU)	H25	IO	OV_{DD}	—
GPIO_PA21/Enet2_TXD[3]/SER2_TXD[3]/ TDMB_TXD[3]/LA5 (LBIU)	H26	IO	OV_{DD}	—
GPIO_PA22/Enet2_RXD[0]/SER2_RXD[0]/ TDMB_RXD[0]/LA6 (LBIU)	C25	IO	OV_{DD}	—
GPIO_PA23/Enet2_RXD[1]/SER2_RXD[1]/ TDMB_RXD[1]/LA7 (LBIU)	C26	IO	OV_{DD}	—
GPIO_PA24/Enet2_RXD[2]/SER2_RXD[2]/ TDMB_RXD[2]/LA8 (LBIU)	D25	IO	OV_{DD}	—
GPIO_PA25/Enet2_RXD[3]/SER2_RXD[3]/ TDMB_RXD[3]/LA9 (LBIU)	D26	IO	OV_{DD}	—

Table 55. MPC8323E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
GPIO_PC10/UPC1_RxDATA[2]/SER5_RXD[2]	B21	IO	OV_{DD}	—
GPIO_PC11/UPC1_RxDATA[3]/SER5_RXD[3]	A20	IO	OV_{DD}	—
GPIO_PC12/UPC1_RxDATA[4]	D19	IO	OV_{DD}	—
GPIO_PC13/UPC1_RxDATA[5]/LSRCID0	C18	IO	OV_{DD}	—
GPIO_PC14/UPC1_RxDATA[6]/LSRCID1	D18	IO	OV_{DD}	—
GPIO_PC15/UPC1_RxDATA[7]/LSRCID2	A25	IO	OV_{DD}	—
GPIO_PC16/UPC1_TxADDR[0]	C21	IO	OV_{DD}	—
GPIO_PC17/UPC1_TxADDR[1]/LSRCID3	D22	IO	OV_{DD}	—
GPIO_PC18/UPC1_TxADDR[2]/LSRCID4	C23	IO	OV_{DD}	—
GPIO_PC19/UPC1_TxADDR[3]/LDVAL	D23	IO	OV_{DD}	—
GPIO_PC20/UPC1_RxADDR[0]	C17	IO	OV_{DD}	—
GPIO_PC21/UPC1_RxADDR[1]	D17	IO	OV_{DD}	—
GPIO_PC22/UPC1_RxADDR[2]	C16	IO	OV_{DD}	—
GPIO_PC23/UPC1_RxADDR[3]	D16	IO	OV_{DD}	—
GPIO_PC24/UPC1_RxSOC/SER5_CD	A16	IO	OV_{DD}	—
GPIO_PC25/UPC1_RxCLAV	D20	IO	OV_{DD}	—
GPIO_PC26/UPC1_RxPRTY/CE_EXT_REQ2	E23	IO	OV_{DD}	—
GPIO_PC27/UPC1_RxEN	B17	IO	OV_{DD}	—
GPIO_PC28/UPC1_TxSOC	B22	IO	OV_{DD}	—
GPIO_PC29/UPC1_TxCLAV/SER5_CTS	A17	IO	OV_{DD}	—
GPIO_PC30/UPC1_TxPRTY	A22	IO	OV_{DD}	—
GPIO_PC31/UPC1_TxEN/SER5_RTS	C20	IO	OV_{DD}	—
GPIO_PD0/SPIMOSI	A2	IO	OV_{DD}	—
GPIO_PD1/SPIMISO	B2	IO	OV_{DD}	—
GPIO_PD2/SPICLK	B3	IO	OV_{DD}	—
GPIO_PD3/SPISEL	A3	IO	OV_{DD}	—
GPIO_PD4/SPI_MDIO/CE_MUX_MDIO	A4	IO	OV_{DD}	—
GPIO_PD5/SPI_MDC/CE_MUX_MDC	B4	IO	OV_{DD}	—
GPIO_PD6/CLK8/BRGO16/CE_EXT_REQ3	F24	IO	OV_{DD}	—
GPIO_PD7/GTM1_TIN1/GTM2_TIN2/CLK5	G24	IO	OV_{DD}	—
GPIO_PD8/$\overline{\text{GTM1\_TGATE1}}$/$\overline{\text{GTM2\_TGATE2}}$/CLK6	H24	IO	OV_{DD}	—
GPIO_PD9/$\overline{\text{GTM1\_TOUT1}}$	D24	IO	OV_{DD}	—

shows the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

Table 59. CSB Frequency Options

CFG_CLKIN_DIV_B at Reset[1]	SPMF	*csb_clk* : Input Clock Ratio [2]	Input Clock Frequency (MHz)[2]		
			25	33.33	66.67
			csb_clk Frequency (MHz)		
High	0010	2 : 1			133
High	0011	3 : 1		100	
High	0100	4 : 1	100	133	
High	0101	5 : 1	125		
High	0110	6 : 1			
High	0111	7 : 1			
High	1000	8 : 1			
High	1001	9 : 1			
High	1010	10 : 1			
High	1011	11 : 1			
High	1100	12 : 1			
High	1101	13 : 1			
High	1110	14 : 1			
High	1111	15 : 1			
High	0000	16 : 1			
Low	0010	2 : 1			133
Low	0011	3 : 1		100	
Low	0100	4 : 1		133	
Low	0101	5 : 1			
Low	0110	6 : 1			
Low	0111	7 : 1			
Low	1000	8 : 1			
Low	1001	9 : 1			
Low	1010	10 : 1			
Low	1011	11 : 1			
Low	1100	12 : 1			
Low	1101	13 : 1			
Low	1110	14 : 1			
Low	1111	15 : 1			
Low	0000	16 : 1			

1 CFG_CLKIN_DIV_B is only used for host mode; CLKIN must be tied low and CFG_CLKIN_DIV_B must be pulled up (high) in agent mode.

2 CLKIN is the input clock in host mode; PCI_CLK is the input clock in agent mode.

22.6 QUICC Engine PLL Configuration

The QUICC Engine PLL is controlled by the RCWL[CEPMF] and RCWL[CEPDF] parameters. Table 61 shows the multiplication factor encodings for the QUICC Engine PLL.

Table 61. QUICC Engine PLL Multiplication Factors

RCWL[CEPMF]	RCWL[CEPDF]	QUICC Engine PLL Multiplication Factor = RCWL[CEPMF]/ (1 + RCWL[CEPDF)
00000–00001	0	Reserved
00010	0	× 2
00011	0	× 3
00100	0	× 4
00101	0	× 5
00110	0	× 6
00111	0	× 7
01000	0	× 8
01001–11111	0	Reserved

The RCWL[CEVCOD] denotes the QUICC Engine PLL VCO internal frequency as shown in Table 62.

Table 62. QUICC Engine PLL VCO Divider

RCWL[CEVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider (RCWL[CEVCOD]) must be set properly so that the QUICC Engine VCO frequency is in the range of 300–600 MHz. The QUICC Engine frequency is not restricted by the CSB and core frequencies. The CSB, core, and QUICC Engine frequencies should be selected according to the performance requirements.

The QUICC Engine VCO frequency is derived from the following equations:

$$ce\_clk = (\text{primary clock input} \times \text{CEPMF}) \div (1 + \text{CEPDF})$$

$$\text{QUICC Engine VCO Frequency} = ce\_clk \times \text{VCO divider} \times (1 + \text{CEPDF})$$

Table 64. Package Thermal Characteristics for PBGA (continued)

Characteristic	Board type	Symbol	Value	Unit	Notes
Junction-to-package top	Natural convection	Ψ_{JT}	2	°C/W	6

Notes:
1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

23.2 Thermal Management Information

For the following sections, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$, where $P_{I/O}$ is the power dissipation of the I/O drivers.

23.2.1 Estimation of Junction Temperature with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. As a general statement, the value obtained on a single layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

23.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter

Wakefield Engineering 603-635-5102
33 Bridge St.
Pelham, NH 03076
Internet: www.wakefield.com

Interface material vendors include the following:

Chomerics, Inc. 781-935-4850
77 Dragon Ct.
Woburn, MA 01801
Internet: www.chomerics.com

Dow-Corning Corporation 800-248-2481
Dow-Corning Electronic Materials
P.O. Box 994
Midland, MI 48686-0997
Internet: www.dowcorning.com

Shin-Etsu MicroSi, Inc. 888-642-7674
10028 S. 51st St.
Phoenix, AZ 85044
Internet: www.microsi.com

The Bergquist Company 800-347-4572
18930 West 78th St.
Chanhassen, MN 55317
Internet: www.bergquistcompany.com

23.3 Heat Sink Attachment

When attaching heat sinks to these devices, an interface material is required. The best method is to use thermal grease and a spring clip. The spring clip should connect to the printed-circuit board, either to the board itself, to hooks soldered to the board, or to a plastic stiffener. Avoid attachment forces which would lift the edge of the package or peel the package from the board. Such peeling forces reduce the solder joint lifetime of the package. Recommended maximum force on the top of the package is 10 lb (4.5 kg) force. If an adhesive attachment is planned, the adhesive should be intended for attachment to painted or plastic surfaces and its performance verified under the application requirements.

23.3.1 Experimental Determination of the Junction Temperature with a Heat Sink

When heat sink is used, the junction temperature is determined from a thermocouple inserted at the interface between the case of the package and the interface material. A clearance slot or hole is normally required in the heat sink. Minimizing the size of the clearance is important to minimize the change in thermal performance caused by removing part of the thermal interface to the heat sink. Because of the experimental difficulties with this technique, many engineers measure the heat sink temperature and then back calculate the case temperature using a separate measurement of the thermal resistance of the

Table 67. Document Revision History

Rev. No.	Date	Substantive Change(s)
2	4/2008	• Removed Figures 2 and 3 overshoot and undershoot voltage specs from Section 2.1.2, "Power Supply Voltage Specification," and footnotes 4 and 5 from Table 1. • Corrected QUIESCE signal to be an output signal in Table 55. • Added column for GVDD (1.8 V) - DDR2 - to Table 6 with 0.212-W typical power dissipation. • Added Figure 4 DDR input timing diagram. • Removed CE_TRB* and CE_PIO* signals from Table 55. • Added three local bus AC specifications to Table 30 (duty cycle, jitter, delay between input clock and local bus clock). • Added row in Table 2 stating junction temperature range of 0 to 105•C. • Modified Section 2.2, "Power Sequencing," to include $\overline{\text{PORESET}}$ requirement.
1	6/2007	Correction to descriptive text in Section 2.2.
0	6/2007	Initial release.